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EE241B : Advanced Digital Circuits Lecture 10 – Latch Timing **Borivoje Nikolić**

February 24, 2020, imore: Report: iPhone 12 to have new short-range WiFi standard, AirTags to charge like Apple Watch

A new report claims that Apple's unannounced iPhone 12 will feature a new short-range WiFi technology, called 802.11ay.

This is a rumor – but it would be cool!





Announcements

- Response to project abstracts today, by e-mail
 - Team web pages
 - Be careful not to leak proprietary info (interface tools via Hammer)
- Quiz 1 today
- Reading
- Chapter 11 (Partovi) in Chandrakasan, Fox, Bowhill



Outline

- Module 3
 - Flip-flop timing
 - Latch-based timing

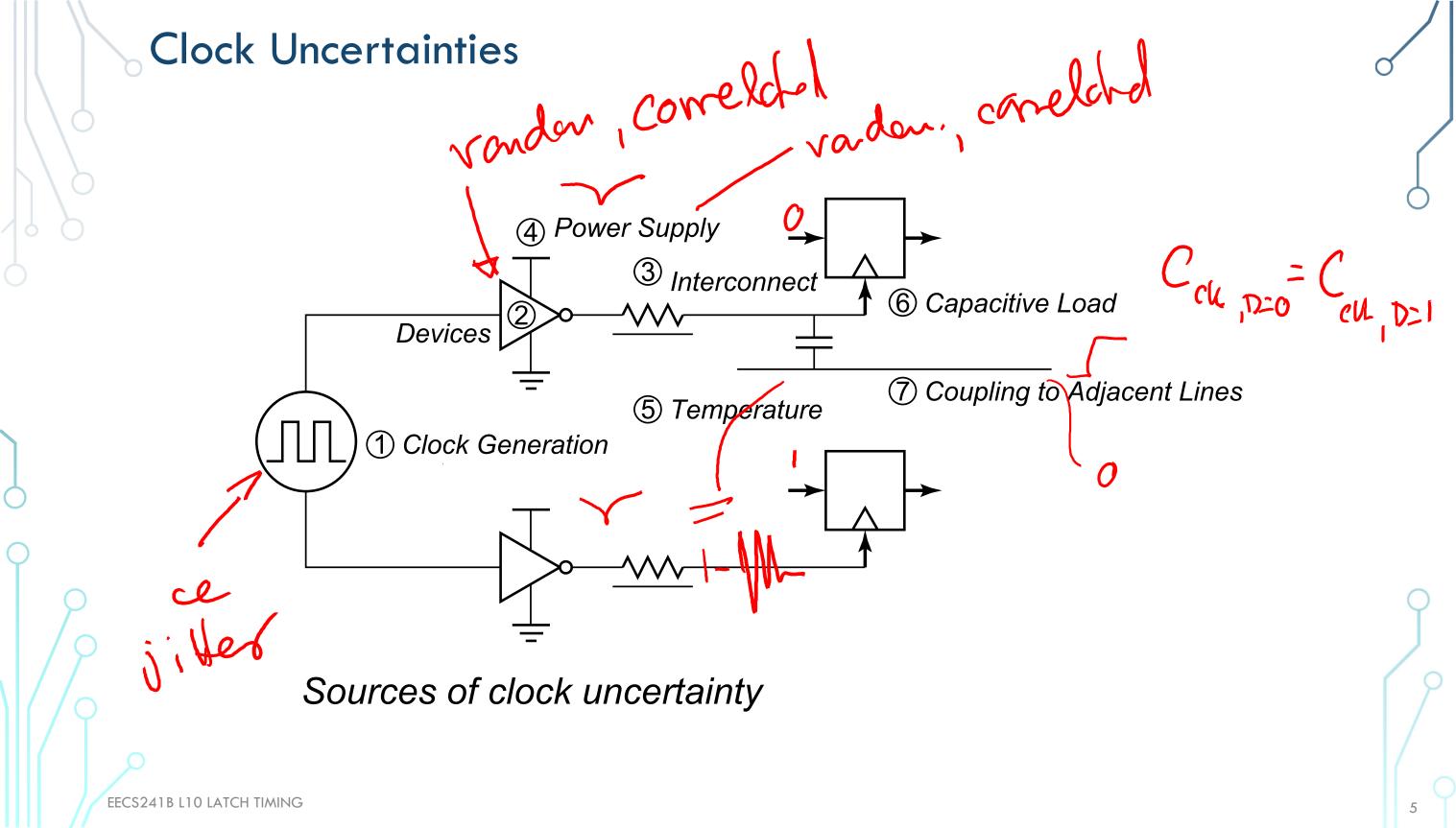




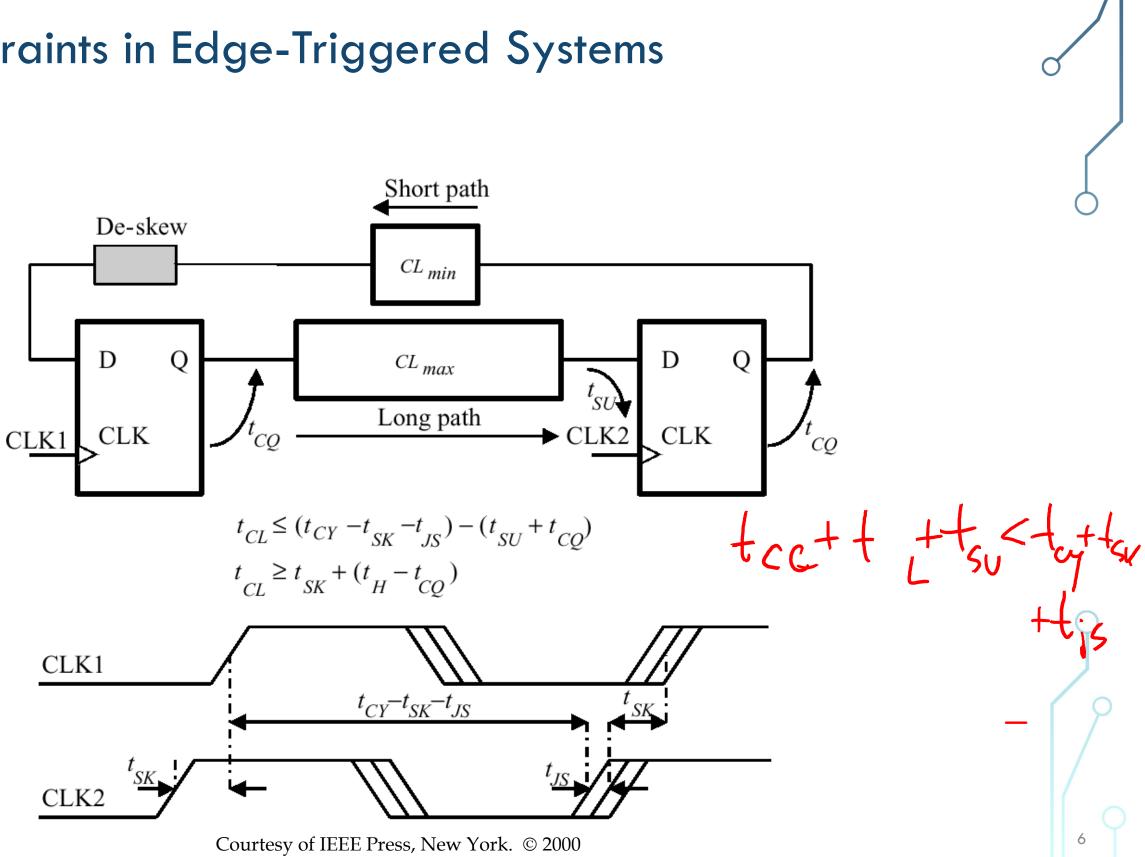
3. Design for Performance3.A Flip-Flop Timing







Clock Constraints in Edge-Triggered Systems



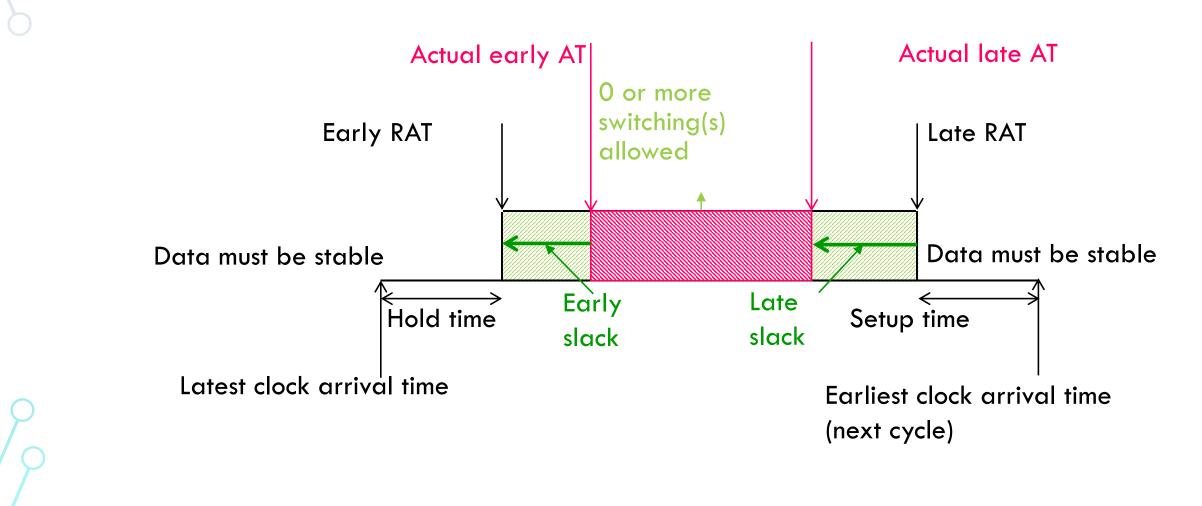


3.B Timing with Uncertainty/Variations





Pictorial View of Setup and Hold Tests



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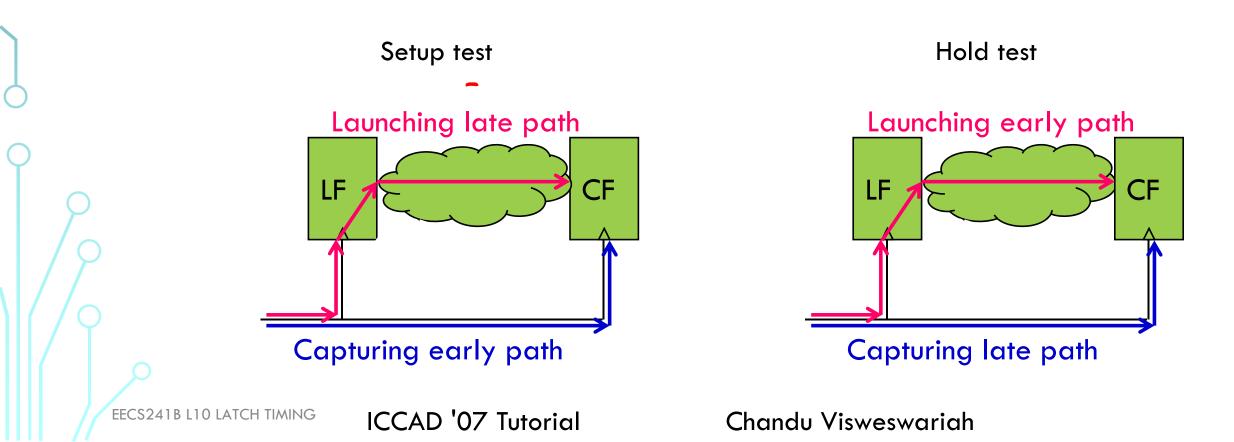
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Handling of Across-Chip Variation

- Each gate has a range of delay: [lb, ub]
 - The lower bound is used for <u>early timing</u>
 - The upper bound is used for <u>late timing</u>
- This is called an <u>early/late split</u>
- Static timing obtains bounds on timing slacks
 - Timing is performed as one forward pass and one backward pass





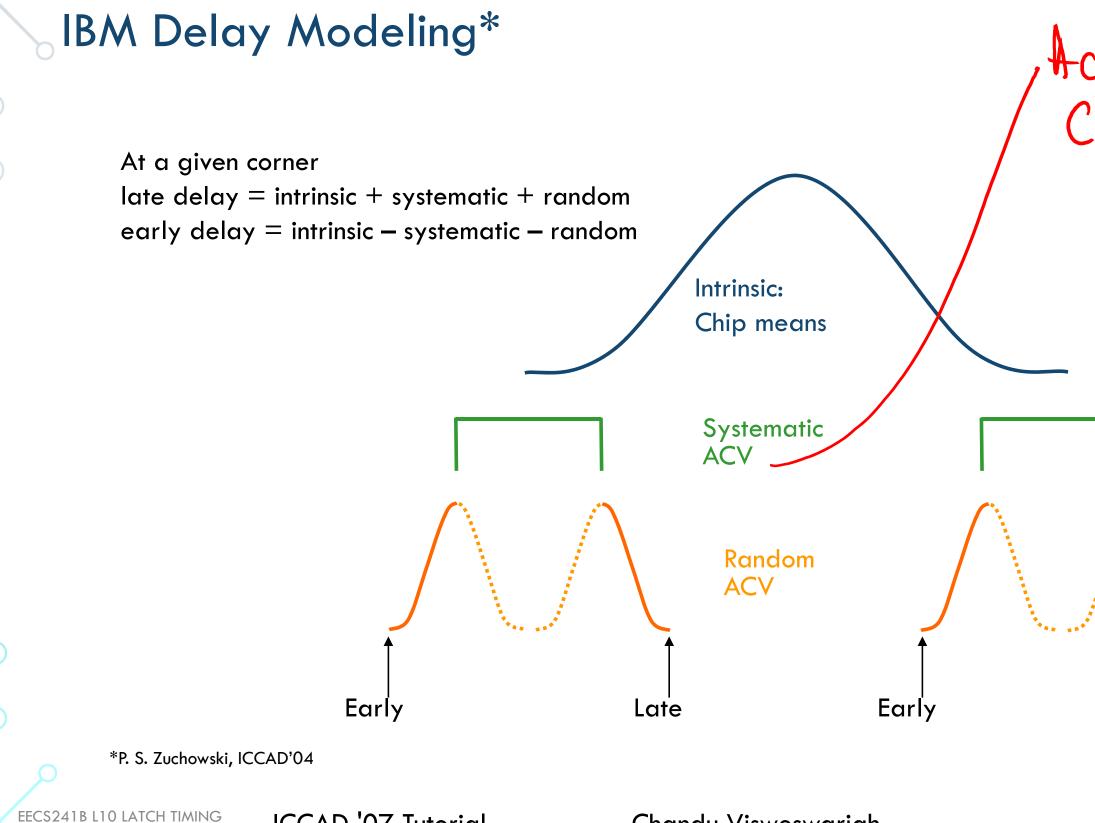
How is the Early/Late Split Computed?

- The best way is to take known effects into account during characterization of library cells
 - History effect, simultaneous switching, pre-charging of internal nodes, etc.
 - This drives separate characterization for early and late; this is the most accurate method
- Failing that, the most common method is derating factors
 - Example: Late delay = library delay * 1.05 Early delay = library delay * 0.95
- The IBM way of achieving derating is LCD factors (Linear Combination of Delay) (FC=fast chip, SC=slow chip, see next page)
 - Late delay = $\alpha_L * FC_{delay} + \beta_L * NOM_{delay} + \gamma_L * SC_{delay}$ Early delay = $\alpha_F * FC_{delay} + \beta_F * NOM_{delay} + \gamma_F * SC_{delay}$
 - Across-chip variation is therefore assumed to be a fixed proportion of chip-to-chip variation for each cell type

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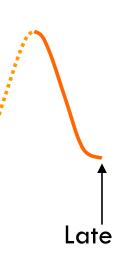






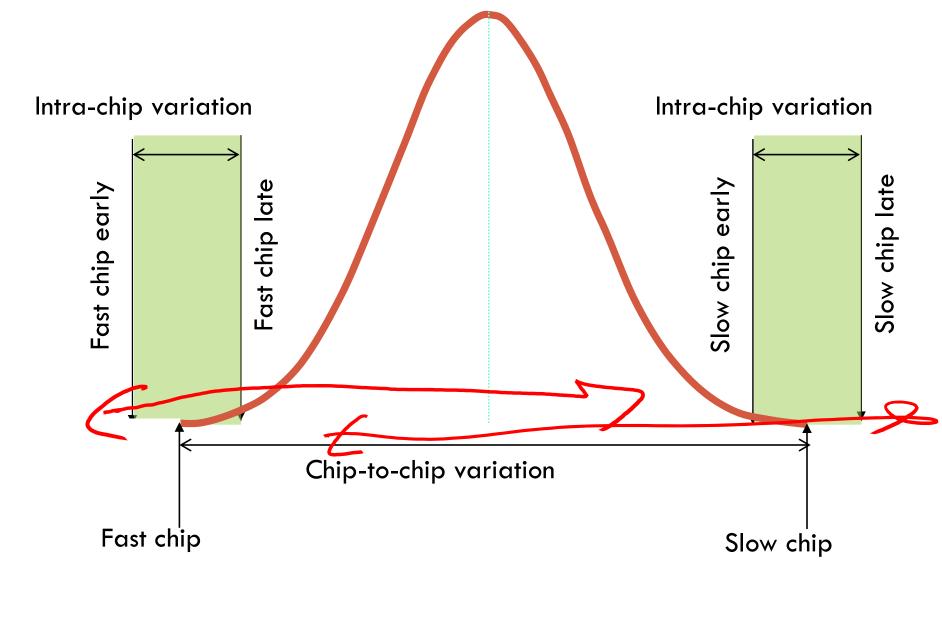
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Traditional Timing Corners



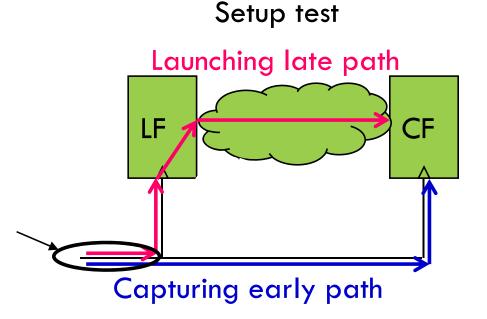
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The Problem with an Early/Late Split

- The early/late split is very useful
 - Allows bounds during delay modeling
 - Any <u>unknown or hard-to-model effect</u> can be swept under the rug of an early/late split
- But, it has problems
 - Additional pessimism (which may be desirable)
 - Unnecessary pessimism (which is <u>never desirable</u>)



This physically common portion can't be both fast and slow at the same time

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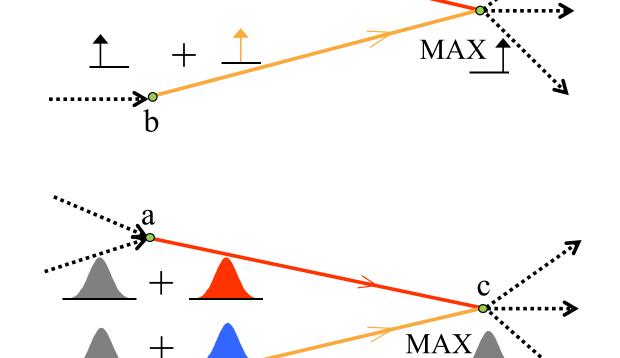
How to Have Less Pessimism?

- Common path pessimism removal
- Account for correlations
- Credit for statistical averaging of random



Statistical Timing

Deterministic



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b

a

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Statistical

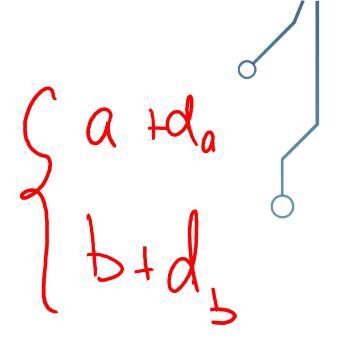
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Chandu Visweswariah

max

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Statistical Max Operation

$$A = a_0 + \sum_{i=1}^{n} a_i \Delta X_i + a_{n+1} \Delta R_a$$

$$B = b_0 + \sum_{i=1}^{n} b_i \Delta X_i + b_{n+1} \Delta R_b$$

$$\sigma_A = \sqrt{\sum_{i=1}^{n+1} a_i^2}$$

$$\sigma_B = \sqrt{\sum_{i=1}^{n+1} b_i^2}$$

$$\rho = \frac{\sum_{i=1}^{n} a_i b_i}{\sigma_A \sigma_B}$$

$$\theta \equiv (\sigma_A^2 + \sigma_B^2 - 2\rho \sigma_A \sigma_B)^{1/2}$$

$$t = \Phi \left[\frac{a_0 - b_0}{\theta}\right]$$

$$E[max(A, B)] = a_0 t + b_0 (1 - t) + \theta \phi \left[\frac{a_0 - b_0}{\theta}\right]$$

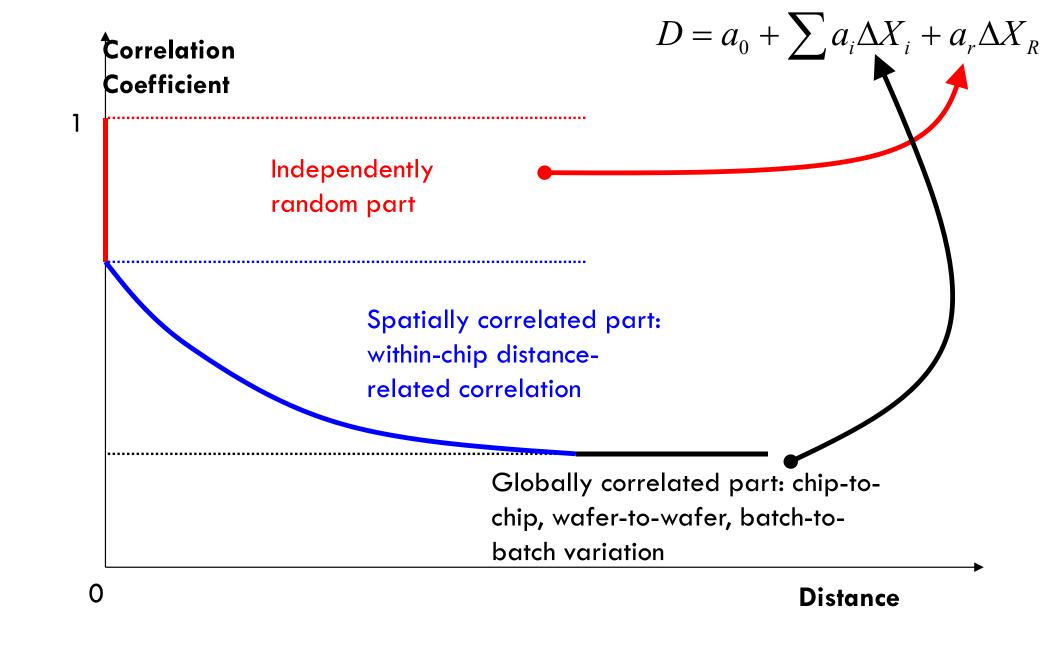
$$E[max(A, B)]^2 = (\sigma_A^2 + a_0^2) t + (\sigma_B^2 + b_0^2) (1 - t) + (a_0 + b_0) \theta \phi \left[\frac{a_0 - b_0}{\theta}\right]$$

*C. E. Clark, "The greatest of a finite set of random variables," OR Journal, March-April 1961, pp. 145–162 **M. Cain, "The moment-generating function of the minimum of bivariate normal random variables," American Statistician, May '94, 48(2)





Unified View of Correlations



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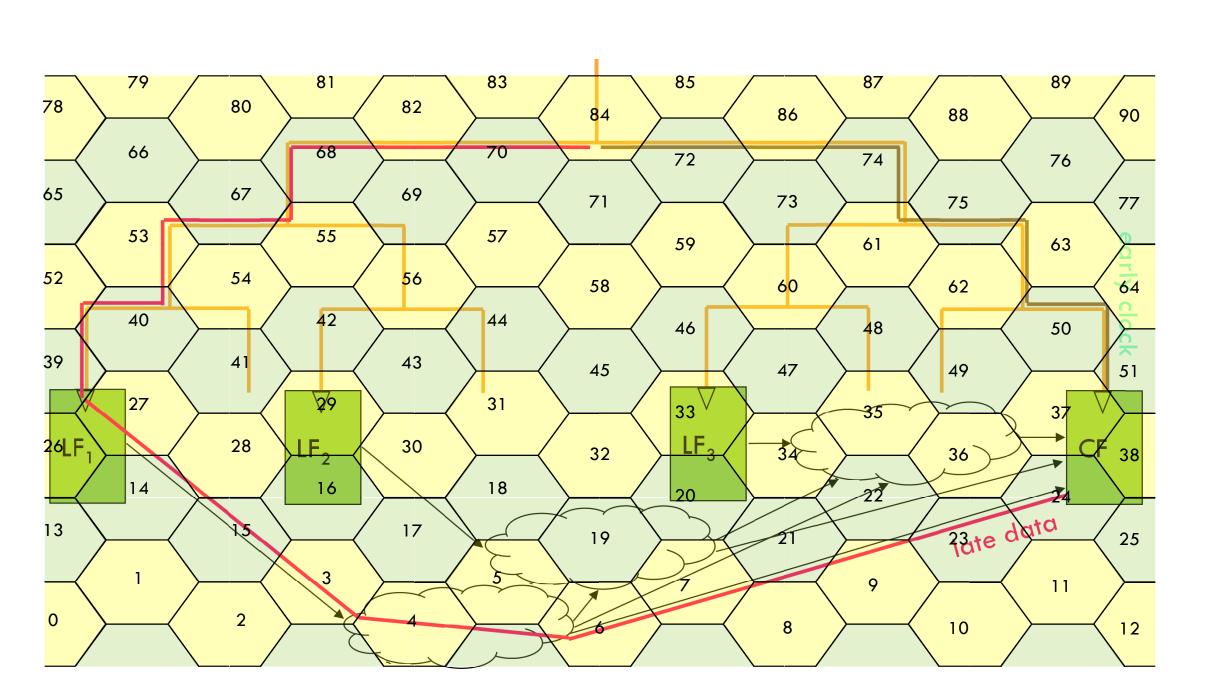
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Spatial Correlation vs. Early/Late Split



Dependence on common virtual variables cancels out at the timing test EECS241B L10 LATCH TIMING ICCAD '07 Tutorial Chandu Visweswariah





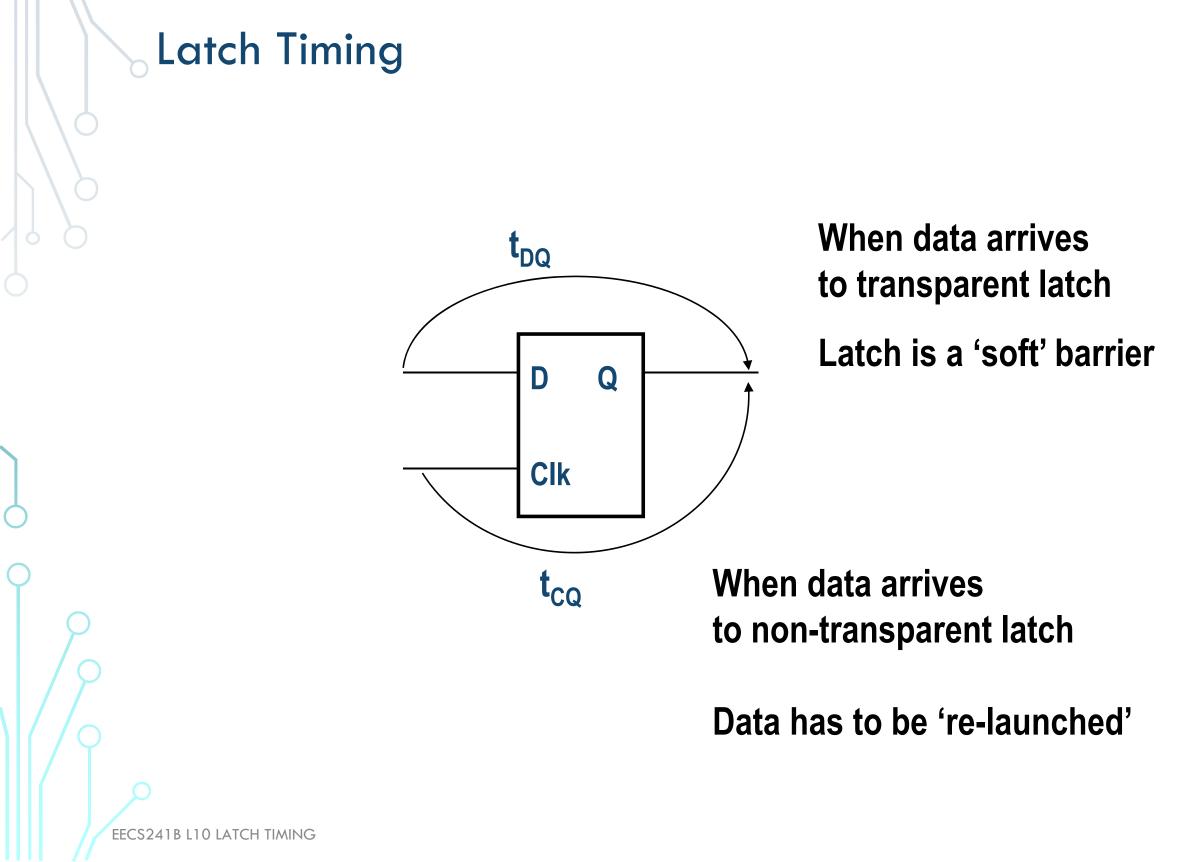
3.C Latch Timing



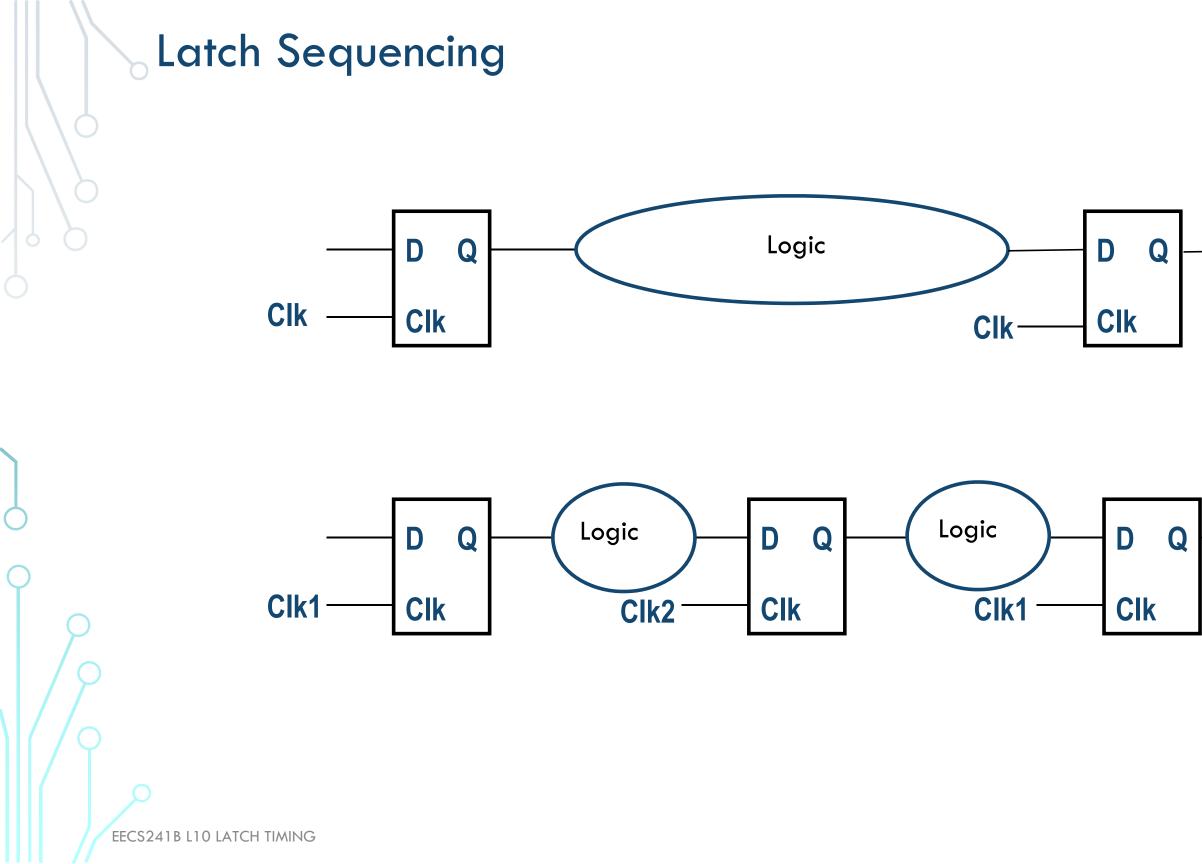
Key Point

- Latch-based sequencing can improve performance, but is more complicated
 - Timing analysis not limited to a consecutive pair of latches

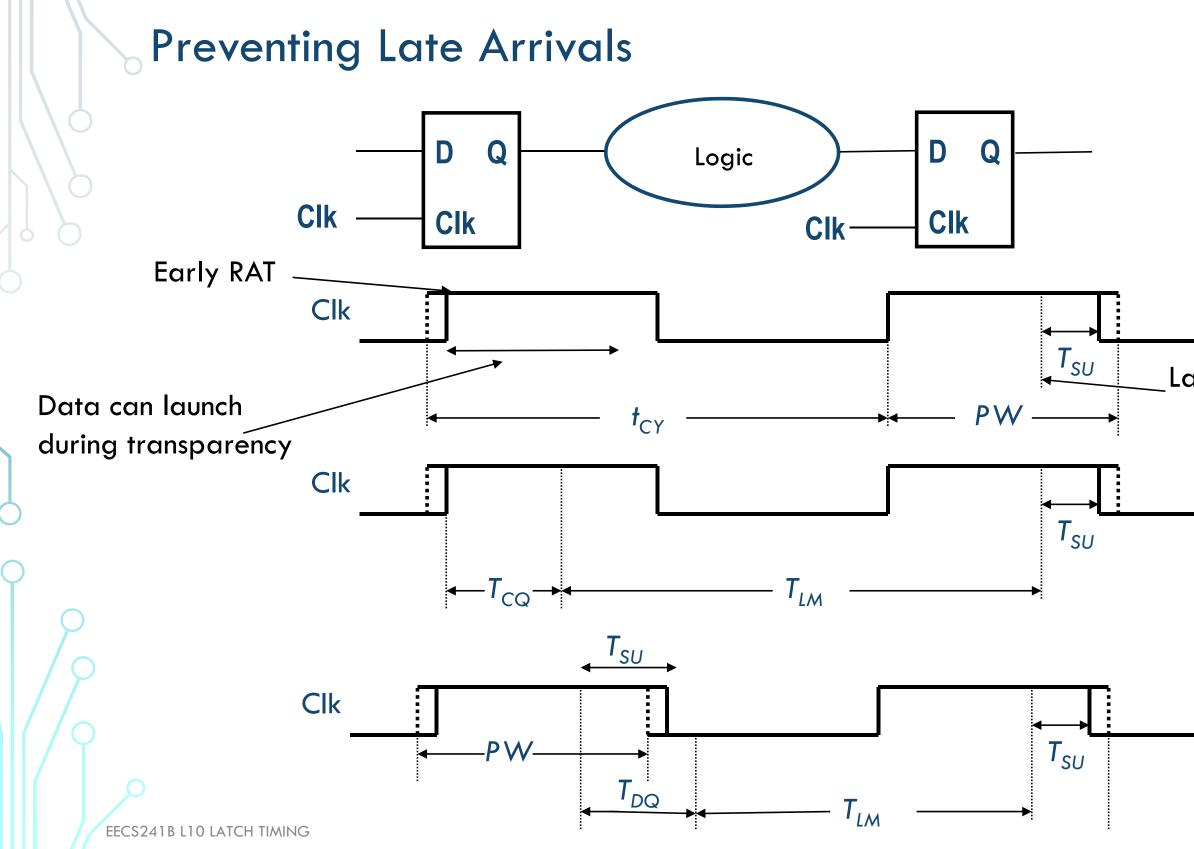
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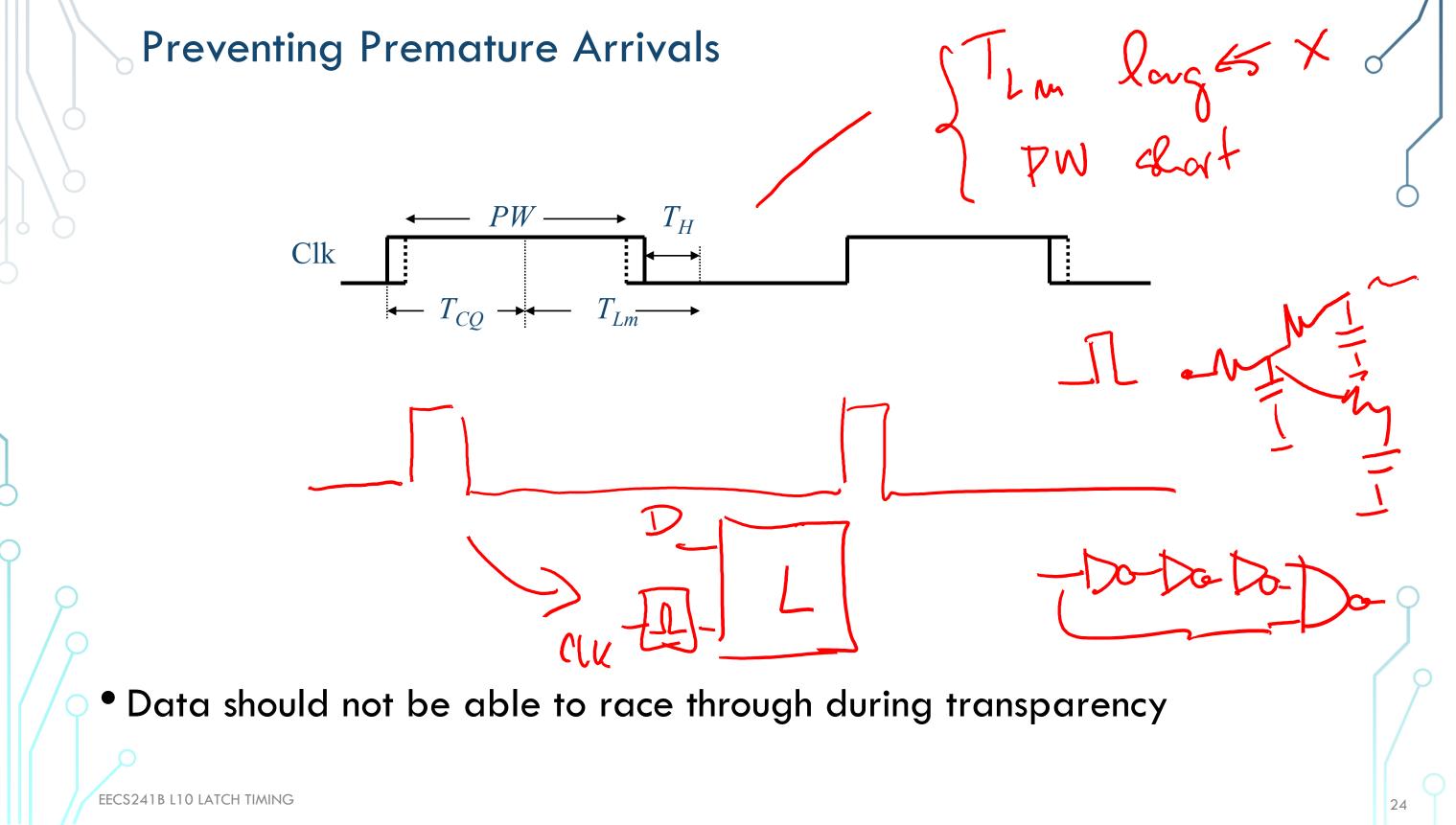




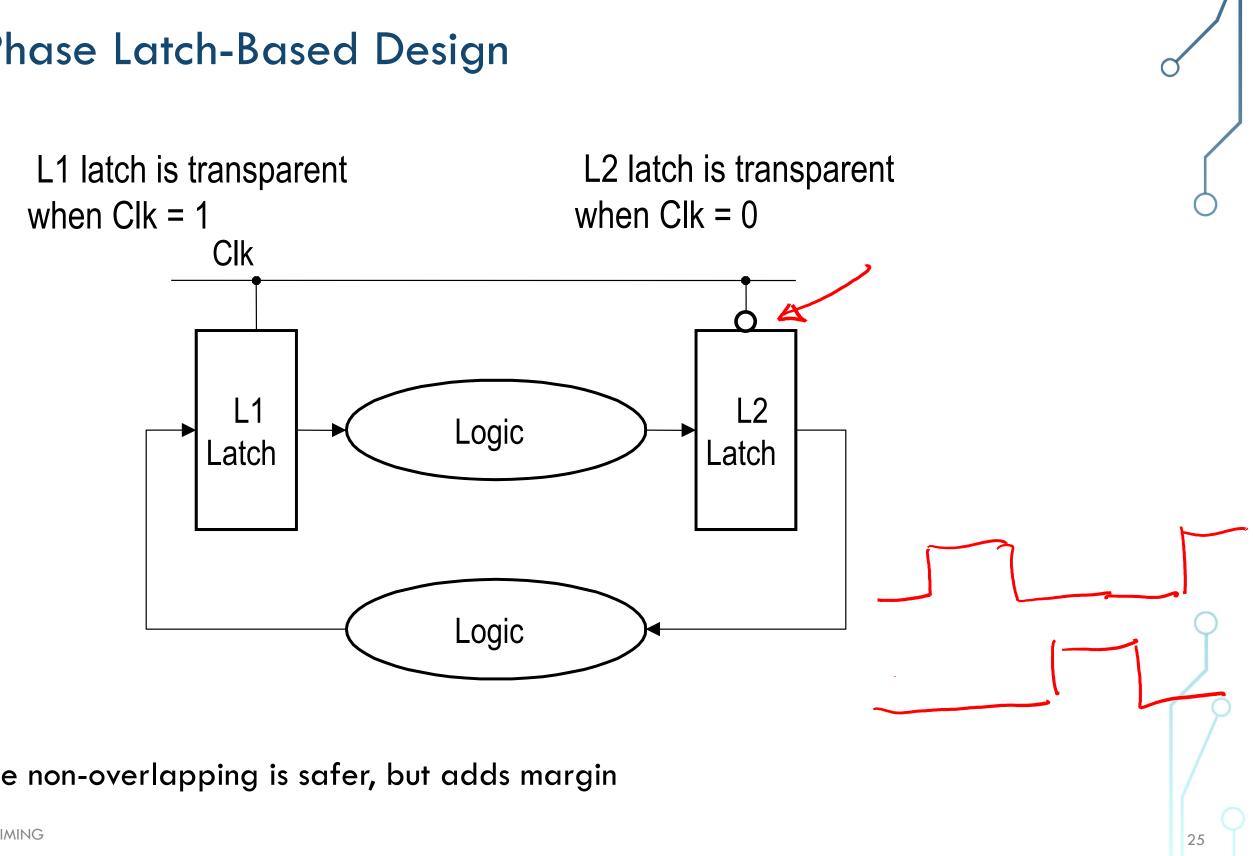


Late RAT





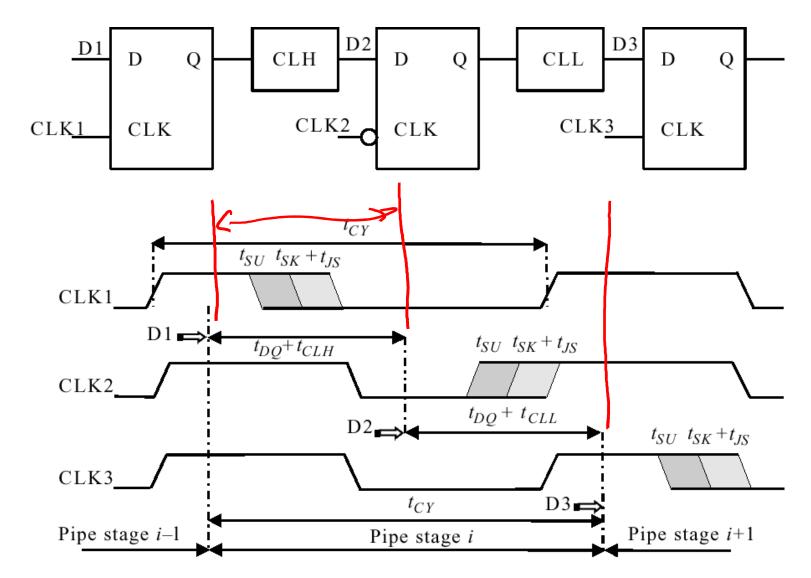
Two-Phase Latch-Based Design



Two-phase non-overlapping is safer, but adds margin

Latch-Based Timing

Single-phase, two-latch

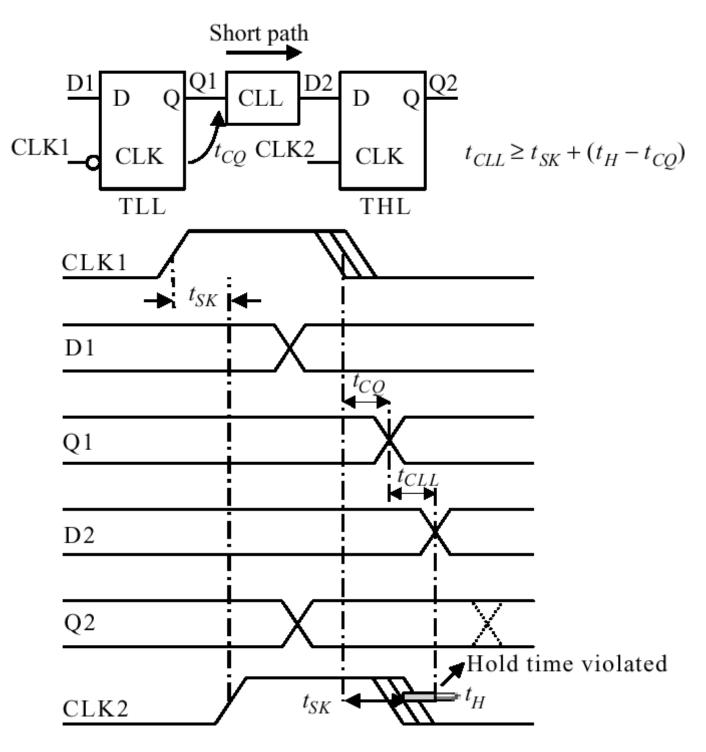


As long as transitions are within the assertion period of the latch, no impact of position of clock edges



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Latch Design and Hold Times

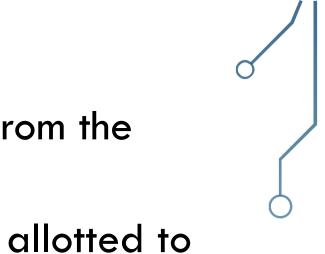




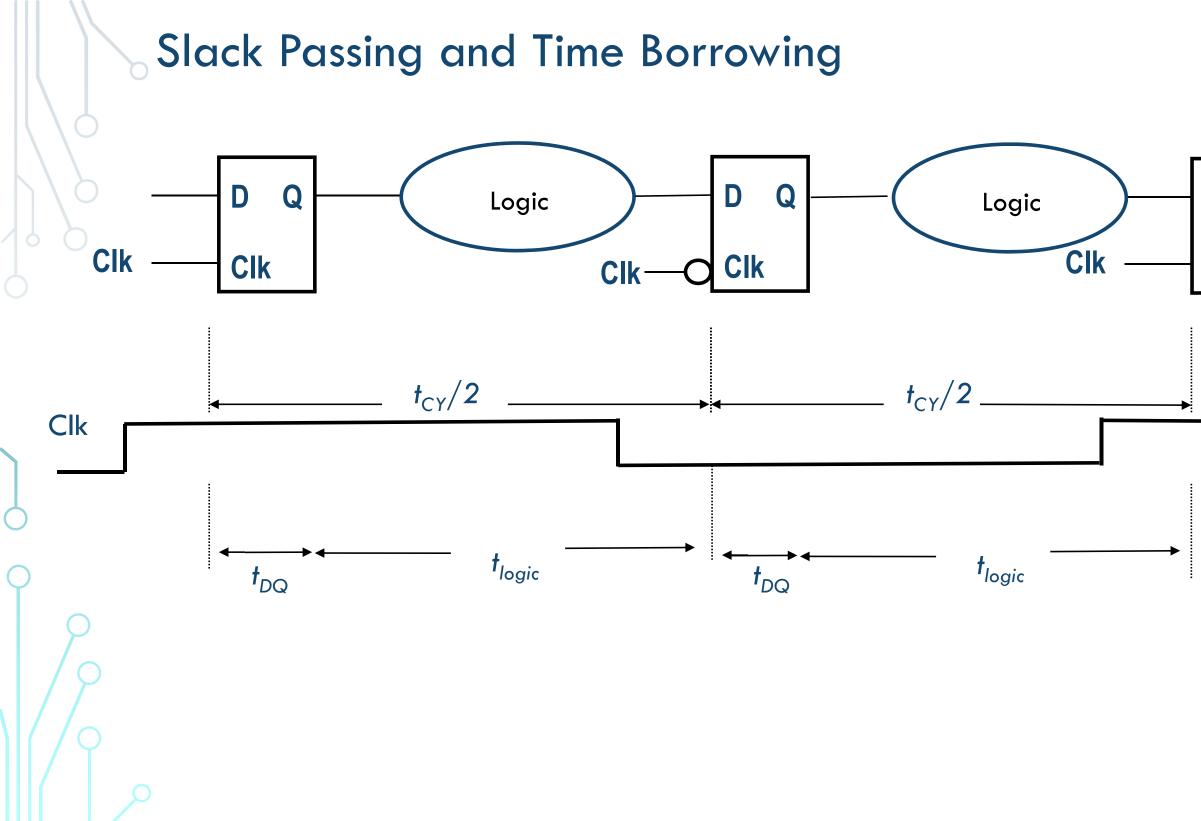
Soft-Edge Properties of Latches

- Slack passing logical partition uses left over time (slack) from the previous partition
- Time borrowing logical partition utilizes a portion of time allotted to the next partition
- Makes most impact in unbalanced pipelines

Bernstein et al, Chapter 8, Chandrakasan, Chap 11 (by Partovi)

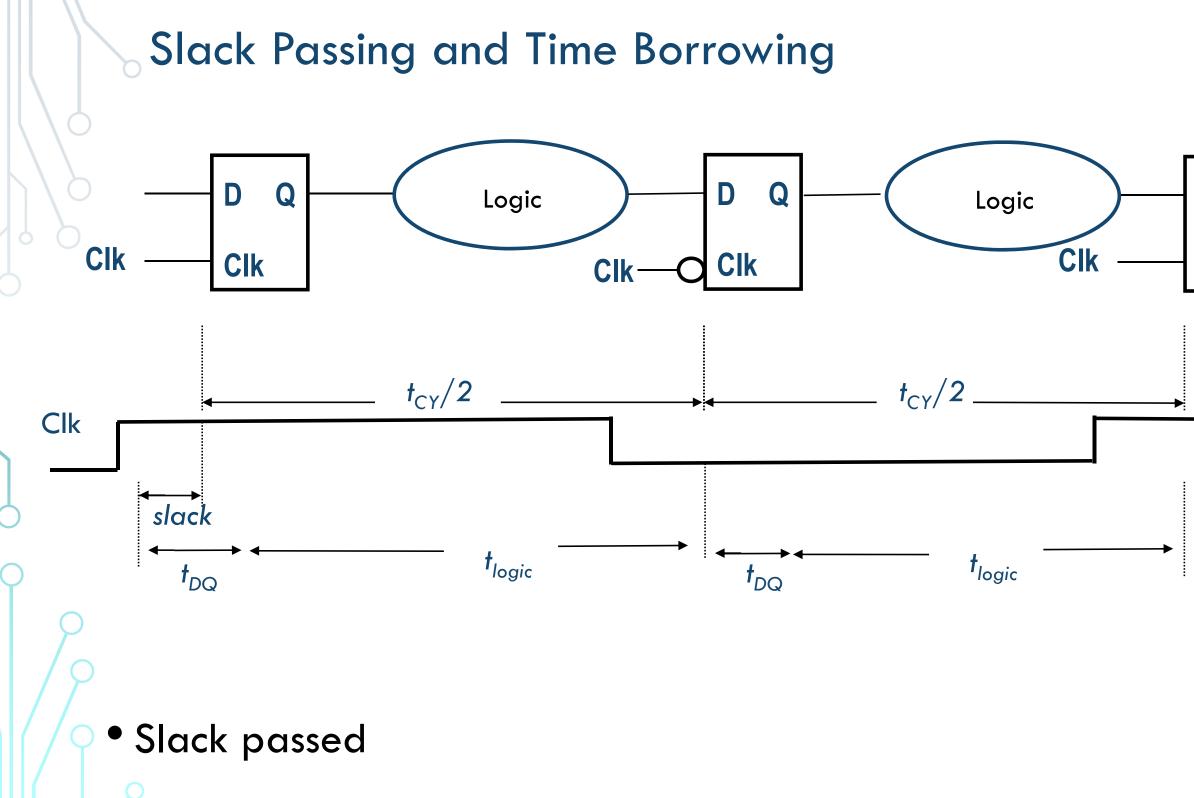








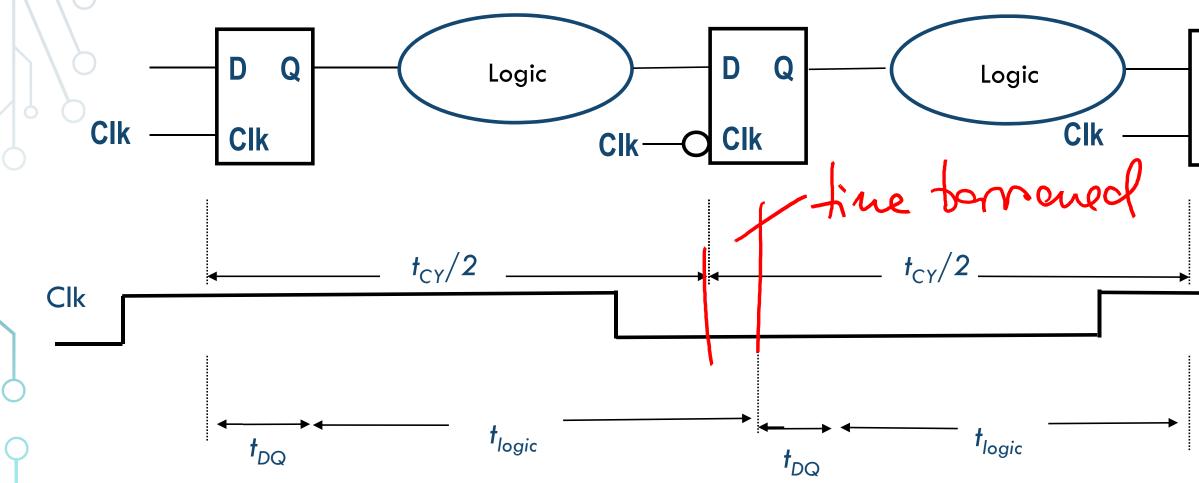










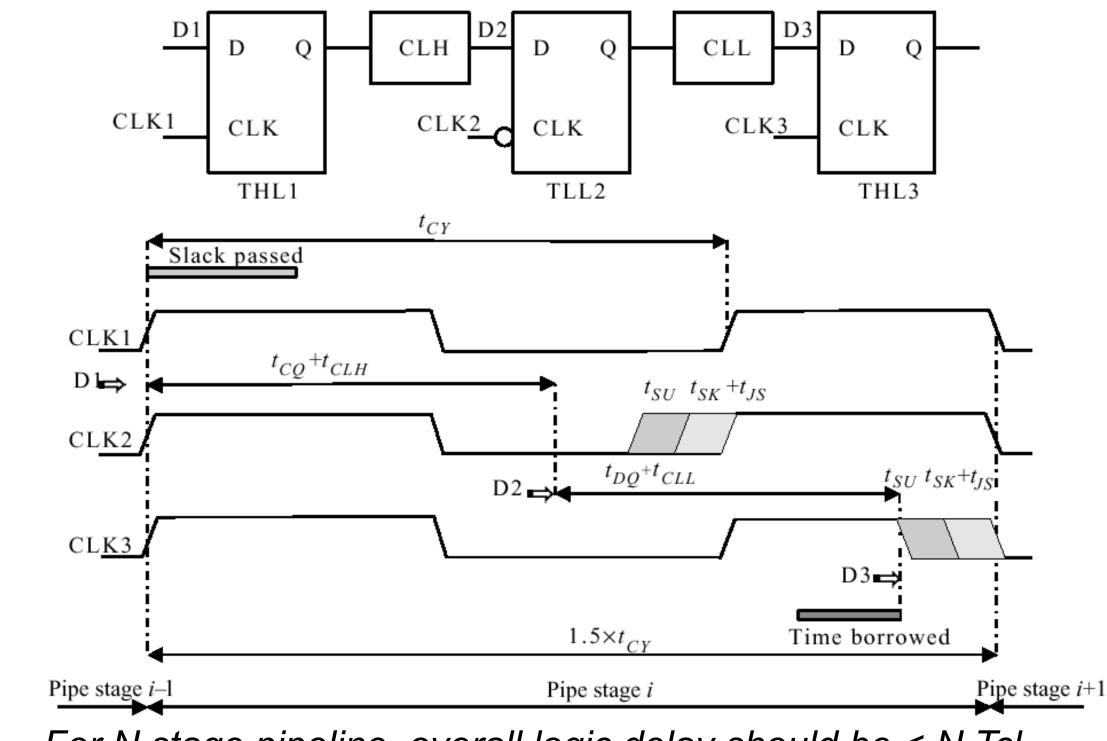


• Time borrowed





Slack-Passing and Cycle Borrowing



TATOR FOR Stage pipeline, overall logic delay should be < N Tcl EECS241B L10



Next Lecture

• Flip-flops

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